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Standard Test Method for **Exposure of Membrane Switches a Membrane Switch or Printed Electronic Device to Temperature and Relative** Humidity¹

This standard is issued under the fixed designation F1596; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ε) indicates an editorial change since the last revision or reapproval.

1. Scope

- 1.1 This test method covers a procedure for temperature and humidity cycling of membrane switches a membrane switch or printed electronic device.
- 1.2 This test method is performed to evaluate the properties of materials used in the construction of membrane switch or printed electronic assemblies as they are influenced by the absorption and diffusion of moisture and moisture vapor. This is an accelerated environmental test, accomplished by the continuous exposure of the test specimen to high relative humidity at an elevated temperature. Absorption of moisture by many materials results in swelling, which destroys their functional utility, causes loss of physical strength, and changes in other mechanical properties. Insulating materials which absorb moisture may suffer degradation of their electrical properties.
 - 1.2.1 Physical changes:
 - 1.2.1.1 Differential contraction or expansion rates or induced strain of dissimilar materials.
 - 1.2.1.2 Cracking of surface coatings.
 - 1.2.1.3 Leaking of sealed compartments.
 - 1.2.1.4 Deformation or fracture of components.

 1.2.2 Chemical changes:

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 - 1.2.2.1 Separation of constituents.
 - 1.2.2.2 Failure of chemical agent protection. Cum ent Preview
 - 1.2.3 Electrical changes:
 - 1.2.3.1 Changes in electronic and electrical components.
 - 1.2.3.2 Electronic or mechanical failures due to rapid water of condensate formation.
 - 1.2.3.3 Excessive static electricity.
- 1.3 This test method is not intended to be a thermal shock procedure; a ramp rate between temperature extremes should not exceed 2°C/min.
- 1.4 This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.

2. Referenced Documents

2.1 ASTM Standards:²

F1595 Practice for Viewing Conditions for Visual Inspection of Membrane Switches

F1661 Test Method for Determining the Contact Bounce Time of a Membrane Switch

F1662 Test Method for Verifying the Specified Dielectric Withstand Voltage and Determining the Dielectric Breakdown Voltage of a Membrane Switch

F1663 Test Method for Determining the Capacitance of a Membrane Switch or Printed Electronic Device

¹ This test method is under the jurisdiction of ASTM Committee F01 on Electronics and is the direct responsibility of Subcommittee F01.18 on Membrane Switches Printed Electronics.

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² For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For Annual Book of ASTM Standards volume information, refer to the standard's Document Summary page on the ASTM website.